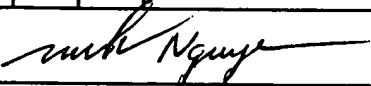
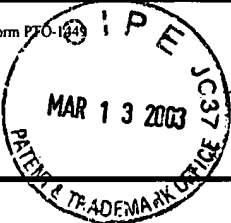


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1680		PRIORITY SERIAL NO. 09/512,968	
LIST OF ART CITED BY APPLICANT (Use separate sheets if necessary)				APPLICANT Micron Technology, Inc.		PRIORITY FILING DATE February 24, 2000	
EV 85429416				PRIORITY GROUP 2850 2823		11000 U.S. PTO 09/025664	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,560,216	12/24/85	Egawa			
VN	AB	4,754,555	7/5/88	Stillman			
VN	AC	5,475,317	12/12/95	Smith			
VN	AD	5,495,667	3/5/96	Farnworth et al.			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE	S/N: 09/032,184; Filed 2/27/98; Akram et al.; Amendment filed 12/18/00; CPA filed 7/28/00; Amendment filed 5/3/00; Amendment filed 8/23/00; Original Application filed 2/27/98; Pending Claims.					
VN	AF	Advertisement for Probe Technology; www.idinet.com ; Interconnect Devices, Inc.; 1 page; 3/6/98					
VN	AG	Good Things Come In Small BGA/CSP Packages; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98					
VN	AH	Product Description for Double Ended Probes, B1052 Series; www.testprobe.com/products/b1052.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AI	Product Description for Test Centers, RM-500 Series Probes; www.testprobe.com/products/rm500.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products; www.testprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AK	Product Description for Ball Grid Probe B1303-C3; www.testprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.; 1 page; 2/4/98.					
VN	AL	Product Description for Test Socket Contacts; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98					
EXAMINER				DATE CONSIDERED			
				02/07/2002 05/29/03			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

04/03/01



EL 465855340

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-1680		SERIAL NO. 09/825,664	
		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT Micron Technology, Inc.			
					FILING DATE April 3, 2001		GROUP 2858	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
✓N	AA	5,670,066	9/23/1997	Barnes et al.	—	—		
✓N	AB	6,377,060 B1	4/23/2002	Burkhart et al.	—	—		
	AC							
	AD							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AE							
	AF							
	AG							
	AH							
	AI		EVO 85429416					
	AJ							
	AK							
	AL							
EXAMINER <i>mil Nguyen</i>				DATE CONSIDERED <i>05/29/03</i>				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								